

ABSTRACT OF THE INVENTION

To provide a capacitance measurement system with which capacitance is measured at a high speed using a semiconductor parametric test system. The capacitance measurement system has test head 104 comprising multiple input/output terminals 152 and 154 that connect the element under test 114, source and measure unit 110 that supplies voltage or current, capacitance measurement unit 108 with an impedance measurement function, and switching matrix 112 that connects the multiple input/output terminals, the source and measure unit, and the capacitance measurement unit.